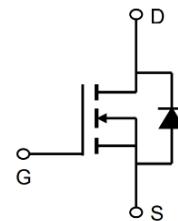


500V N-Channel Enhancement Mode MOSFET
Description

The AP16N50F/P is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.


General Features

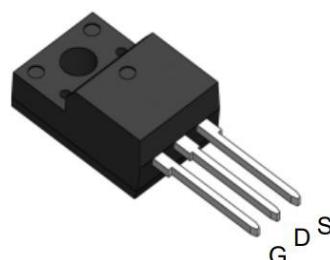
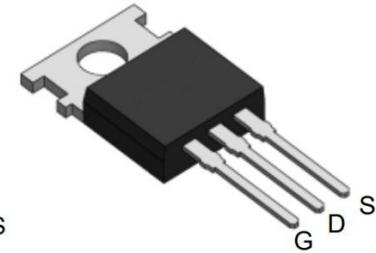
$V_{DS} = 500V$ $I_D = 16A$

$R_{DS(ON)} < 400m\Omega$ @ $V_{GS}=10V$ (**Type: 320m Ω**)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)

TO-220F

TO-220

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP16N50F	TO-220F-3L	AP16N50F XXX YYYY	1000
AP16N50P	TO-220-3L	AP16N50P XXX YYYY	1000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
		TO-220F	
VDSS	Drain-Source Voltage ($V_{GS} = 0V$)	500	V
ID	Continuous Drain Current	16	A
IDM	Pulsed Drain Current (note1)	58	A
VGS	Gate-Source Voltage	± 30	V
EAS	Single Pulse Avalanche Energy (note2)	452	mJ
IAR	Avalanche Current (note1)	14	A
EAR	Repetitive Avalanche Energy (note1)	60	mJ
PD	Power Dissipation ($T_c = 25^\circ C$)	32	W
TJ, Tstg	Operating Junction and Storage Temperature Range	-55~+150	°C
RthJC	Thermal Resistance, Junction-to-Case	4.12	°C/W
RthJA	Thermal Resistance, Junction-to-Ambient	62.5	°C/W



500V N-Channel Enhancement Mode MOSFET
Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
BVDSS	Drain-Source Breakdown Voltage	VGS = 0 V, ID = 250 μA	500	550		V
ΔBVDSS/ ΔTJ	Breakdown Voltage Temperature Coefficient	ID = 250 μA, Referenc ed to 25°C		0.52		V/°C
IDSS	Zero Gate Voltage Drain Current	VDS=500 V, VGS=0V			1	μA
		VDS=400 V, TC=125°C			10	μA
IGSSF	Gate-Body Leakage Current, Forward	VGS= 30V, VDS=0 V			100	nA
IGSSR	Gate-Body Leakage Current, Reverse	VGS=-30 V, VDS=0V			-100	nA
VGS(TH)	Gate Threshold voltage	VDS=VGS, ID=250 uA	2.0	3.0	4.0	V
RDS(On)	Drain-Source on-state resistance	VGS=10V, ID = 6.5A, TJ = 25°C		320	400	mΩ
gFS	Forward Transconductance	VDS = 40 V, ID=6.5A (Note 4)		12.8		S
Ciss	Input capacitance	VDS=25V, VGS=0V, f=1.0MHz		1651		pF
Coss	Output capacitance			188		pF
Crss	Reverse transfer capacitance			7		pF
td(on)	Turn On Delay Time	VDD= 250 V, ID =16 A, RG = 25 Ω (Note 4, 5)		31		ns
tr	Rising Time			43		ns
td(off)	Turn Off Delay Time			106		ns
tf	Fall Time			46		ns
Qg	Total Gate Charge	VDS = 400 V, ID = 13 A, VGS = 10 V (Note 4, 5)		23.5		nC
Qgs	Gate-Source Charge			6.9		nC
Qgd	Gate-Drain Charge			7.4		nC
ISM	Maximum Pulsed Drain-Source Diode Forward Current				52	A
VSD	Diode Forward Voltage	VGS= 0 V, IS = 13 A			1.2	V
trr	Reverse Recovery Time	VGS = 0 V, IS = 13 A, dIF / dt = 100 A/μs (Note 4)		340		ns
Qrr	Reverse Recovery Charge			2.8		μC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . L=4.1Mh IAS=14A, VDD=50V, RG=25Ω, Starting TJ = 25 °C
- 3、The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

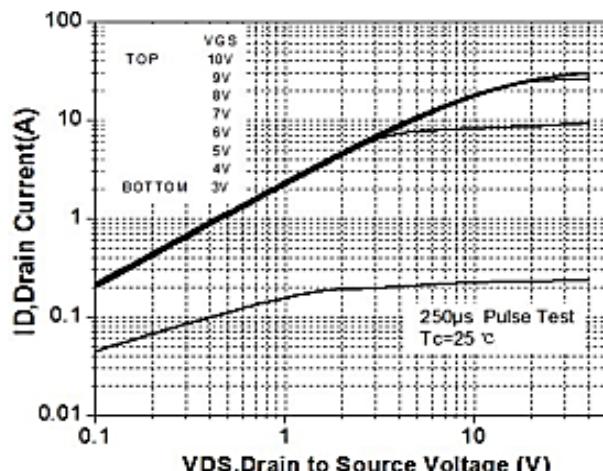


Figure 1. On-Region Characteristics

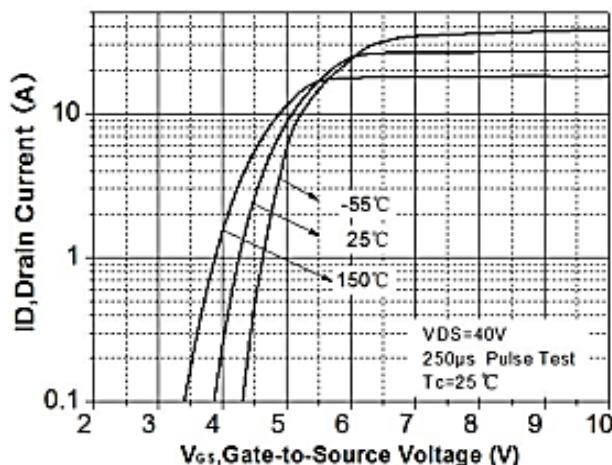


Figure 2. Transfer Characteristics

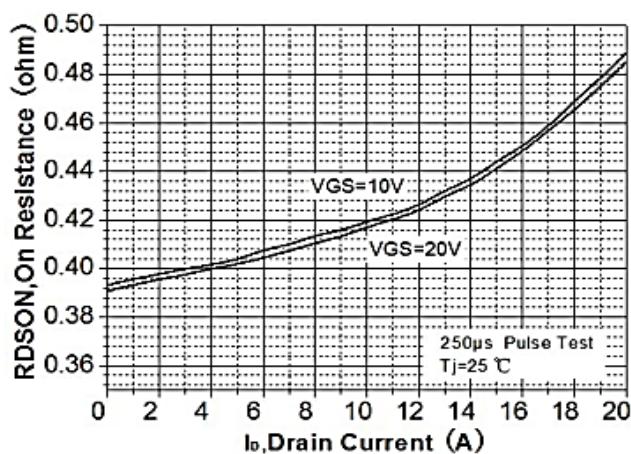


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

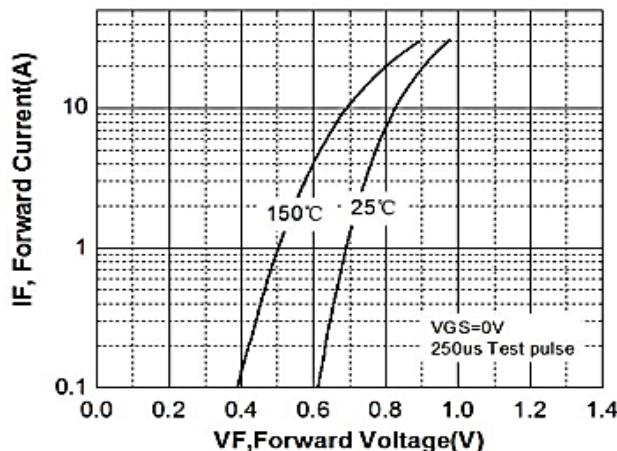


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

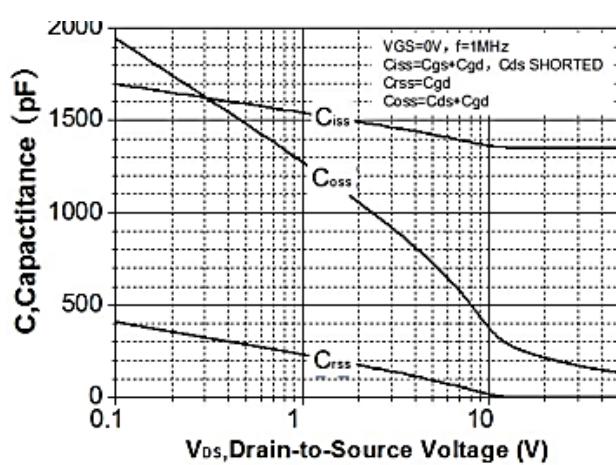


Figure 5. Capacitance Characteristics

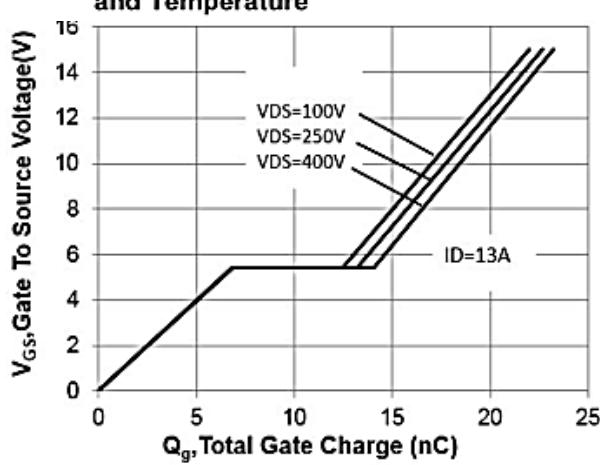


Figure 6. Gate Charge Characteristics

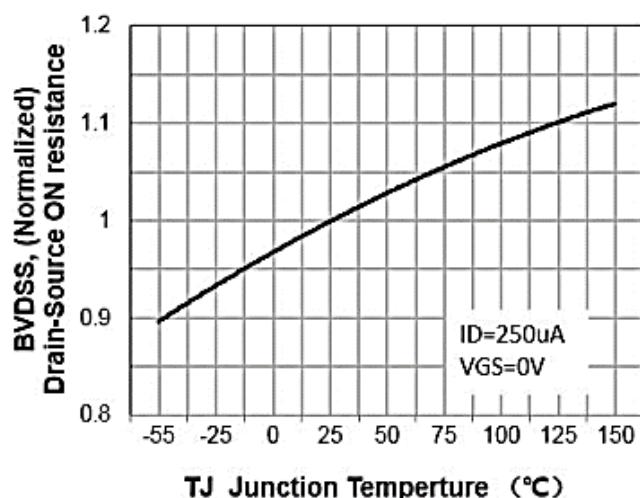
500V N-Channel Enhancement Mode MOSFET


Figure 7. Breakdown Voltage Variation vs Temperature

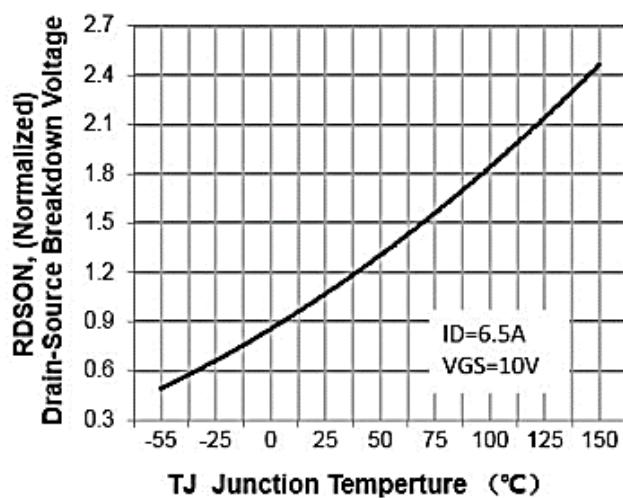


Figure 8. On-Resistance Variation vs Temperature

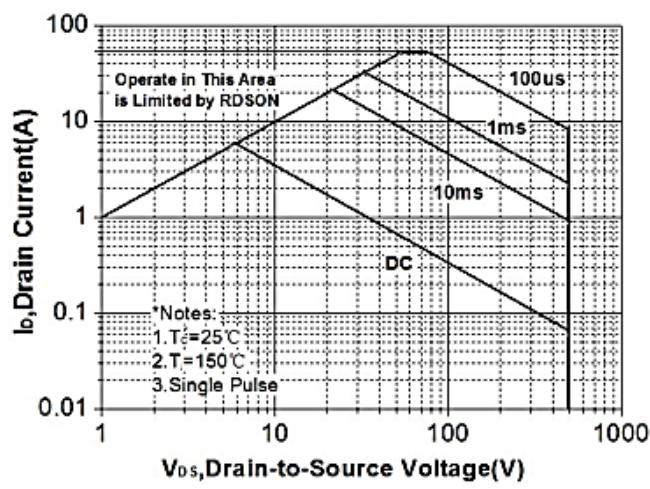


Figure 9. Maximum Safe Operating Area

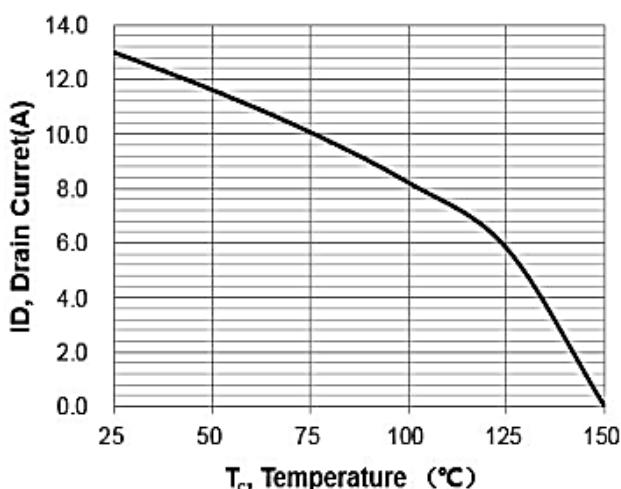


Figure 10. Maximum Drain Current vs Case Temperature

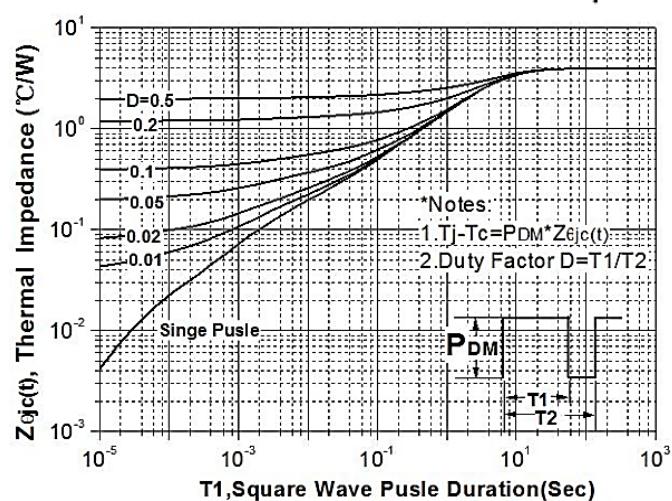
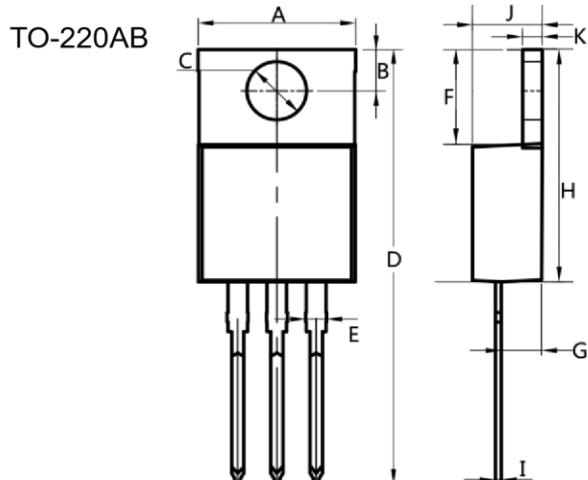
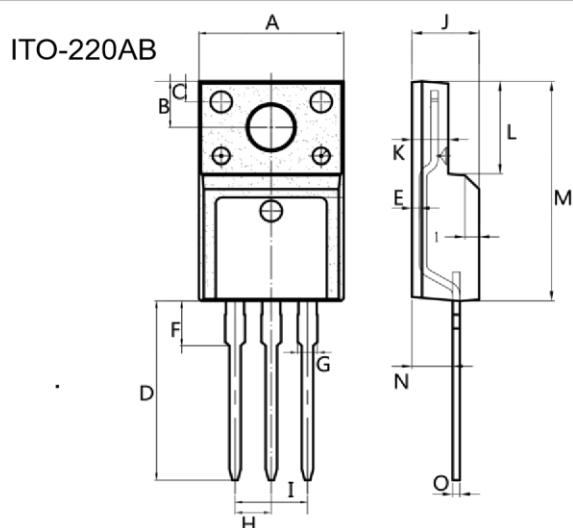


Figure 11. Transient Thermal Response Curve

500V N-Channel Enhancement Mode MOSFET


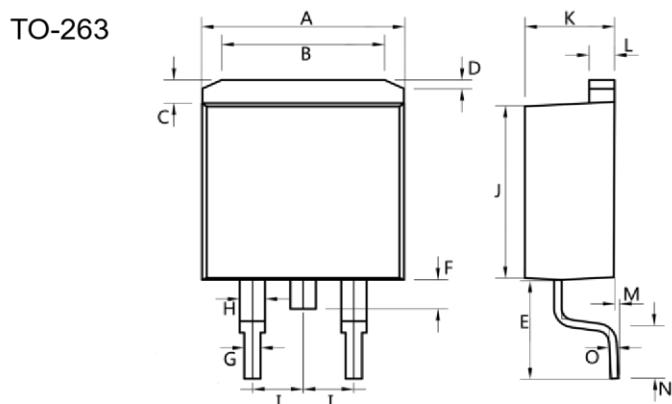
Dim.	Min.	Max.
A	10.0	10.4
B	2.5	3.0
C	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
H	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4

All Dimensions in millimeter



Dim.	Min.	Max.
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	Typ 2.54	
I	Typ 5.08	
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

All Dimensions in millimeter



Dim.	Min.	Max.
A	10.0	10.5
B	7.25	7.75
C	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
H	1.15	1.35
I	Typ 2.54	
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
M	0.02	0.1
N	2.4	2.8
O	0.35	0.45

All Dimensions in millimeter